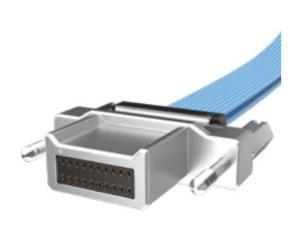


Project Number: Severe Environment Test Report	Tracking Code: CR-971604_Report_Rev_1
Requested by: Tyler Lang	Date: 4/1/2024
Part #: B1SDT-30-28-H-06.0/P1M-30-01-S-D-RA-TR	
Part description: B1SDT/P1M	Tech: John Crawford
Test Start: 8/20/2023	Test Completed: 10/1/2023





SEVERE ENVIRONMENT TEST REPORT
B1SDT/P1M
B1SDT-30-28-H-06.0/P1M-30-01-S-D-RA-TR

Tracking Code: CR-971604_Report_Rev_1	Part #: B1SDT-30-28-H-06.0/P1M-30-01-S-D-RA-TR
	Part description: B1SDT/P1M

REVISION HISTORY

DATA	REV.NUM.	DESCRIPTION	ENG
11/14/2023	1	Initial Issue	PC

Tracking Code: CR-971604_Report_Rev_1	Part #: B1SDT-30-28-H-06.0/P1M-30-01-S-D-RA-TR
	Part description: B1SDT/P1M

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

To perform the following tests: Severe Environment test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364: VITA 47.1

TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Samtec Test PCBs used: PCB-111718-TST/PCB-111720-TST/ PCB-112867-TST-XX.

FLOWCHARTS

Mating/Unmating/Durability

Note: With Humidity (Up to 100% RH, 240 hours, 25°C to 65°C)

Note: From MIL-STD-810G: For chamber control purposes, 100% RH implies as close to 100% RH as possible, but not less than 95%.

Group 1
B1SDT-30-28-H-06.0
P1M-30-01-S-D-RA-TR
8 Assemblies
60 Positions

Step Description

- LLCR (2)
- 2. Mating/Unmating Force (3)
- Cycles
 Quantity = 250 Cycles
- 4. LLCR (2)
- Max Delta = 15 mOhm
- Thermal Shock (4)
 LLCR (2)
- Max Delta = 15 mOhm
- Humidity (1) Non Standard
- LLCR (2)
 Max Delta = 15 mOhm
- Mating/Unmating Force (3)

Group 2

B1SDT-10-28-H-06.0 P1M-10-01-S-D-RA-TR 8 Assemblies

20 Positions

Step Description

- 1. Mating/Unmating Force (3)
- Cycles
 Quantity = 250 Cycles
- 3. Mating/Unmating Force (3)

(1) Humidity = Other

240 Hours

+25°C to +65°C @ 95% RH up to 100% RH

(2) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

- (3) Mating/Unmating Force = EIA-364-13
- (4) Thermal Shock = EIA-364-32

Exposure Time at Temperature Extremes = 1/2 Hour Method A, Test Condition = I (-55°C to +85°C) Test Duration = A-3 (100 Cycles)

Part #: B1SDT-30-28-H-06.0/P1M-30-01-S-D-RA-TR Tracking Code: CR-971604_Report_Rev_1

Part description: B1SDT/P1M

FLOWCHARTS Continued

Mechanical Shock/Random Vibration/LLCR

Group 1 B1SDT-30-28-H-12.0 P1M-30-01-S-D-RA-TR 8 Assemblies

VITA 47.1

Step Description

- LLCR (1)
- Mechanical Shock (2) Non Standard
- Random Vibration (3) Non Standard

Note: Conditions:

1) 5 Hz to 100 Hz, PSD increasing

at 3dB/octave

2) 100 Hz to 1000 Hz 0.10 q^2/Hz

3) 1000 Hz to 2000 HzPSD

decreasing at 3dB/octave

LLCR (1)

Max Delta = 15 mOhm

(1) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max Test Current = 100 mA Max

(2) Mechanical Shock = Other

40G, 11 milliseconds, Half Sine

Number of Shocks = 3 Per Direction, Per Axis, 18 Total

Operating Shock Class OS2

(3) Random Vibration = Other

12 G 'RMS', 5Hz to 2000Hz, 1 Hours/Axis

Vibration Class V3 VITA 47.1

Mechanical Shock/Random Vibration/Event Detection

Group 1 B1SDT-30-28-H-12.0

P1M-30-01-S-D-RA-TR

8 Assemblies

VITA 47.1

Step Description

Nanosecond Event Detection

(Mechanical Shock) (1) - Non Standard

Nanosecond Event Detection

(Random Vibration) (2) - Non Standard

Note: Conditions:

1) 5 Hz to 100 Hz, PSD increasing

at 3dB/octave

2) 100 Hz to 1000 Hz 0.10 g^2/Hz

3) 1000 Hz to 2000 HzPSD

decreasing at 3dB/octave

(1) Nanosecond Event Detection (Mechanical Shock) = Other Use EIA-364-87 for Nanosecond Event Detection: Test Condition = F (50 nanoseconds at 10 ohms) 40G, 11 milliseconds, Half Sine

(2) Nanosecond Event Detection (Random Vibration) = Other Use EIA-364-87 for Nanosecond Event Detection: Test Condition = F (50 nanoseconds at 10 ohms) Random Vibration: 12 G 'RMS', 5Hz to 2000Hz, 1 Hours/Axis, Vibration Class V3 VITA 47.1 Part description: B1SDT/P1M

FLOWCHARTS Continued

Temperature Cycling

Group 1

B1SDT-30-28-H-06.0-2

P1M-30-01-S-D-RA-TR

8 Assemblies

500 Thermal Cycles

Note: Follow procedure as described in MIL-STD-202G, Method 107, Thermal Shock

Step Description

- Continuity (Initial)
- Temperature Cycles (1) Non Standard Cycles = 500 Cycles Continuity = Monitor for 1 MicroSecond Interruptions Throughout
- Continuity (Following Last Cycle)

(1) Temperature Cycles = Other

Max Temperature = 125° C Min Temperature = -65° C Dwell Time = 30 minutes at each extreme Ramp Rate = 10° C/min VITA 47.1

Non-Operating Class Temperature

VITA 47.1

Group 1

B1SDT-30-28-H-06.0

P1M-30-01-S-D-RA-TR

8 Assemblies

Non-Operating Class Temperature

Step Description

LLCR (1)

Max Delta = 15 mOhm

 Temperature Cycle Cycles = 100

Temperature Cycle = -55 $^{\circ}$ C to 105 $^{\circ}$ C

LLCR (1)

Max Delta = 15 mOhm

4. Temperature Cycle

Cycles = 100

Temperature Cycles = -65°C to 125°C

LLCR (1)

Max Delta = 15 mOhm

(1) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max Test Current = 100 mA Max

FLOWCHARTS Continued

DWV @ Altitude

Pin to Pin

Group 1
B1SDT-10-28-H-06.0
P1M-10-01-S-D-RA-TR
3 Assemblies
Custom Group

Step Description

 DWV at Test Voltage (1) - Non Standard Note: Test Voltage to be 300 VAC

Row to Row

Group 2 B1SDT-10-28-H-06.0 P1M-10-01-S-D-RA-TR 3 Assemblies Custom Group

Step Description

L. DWV at Test Voltage (1) - Non Standard Note: Test Voltage to be 300 VAC

(1) DWV at Test Voltage = Other

Test Condition IV = 70,000 ft

DWV test voltage is equal to 75% of the lowest breakdown voltage

Test voltage applied for 60 seconds

Electrostatic Discharge (ESD)

Group 1 B1SDT-30-28-H-06.0 P1M-30-01-S-D-RA-TR 8 Assemblies EN61000-4-2

Step Description

 Exposure To 5kV, 10kV, 15kV, Repeat 10 Times
 Note: The connector shall not be susceptable to damage by ESD events from 0 to 15kV as discharged from a 150 pf capacitor through a 330 ohm resistor.

Tracking Code: CR-971604_Report_Rev_1	Part #: B1SDT-30-28-H-06.0/P1M-30-01-S-D-RA-TR
	Part description: B1SDT/P1M

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL SHOCK:

- 1) OTHER, Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors.
- 2) Test Condition: -65° C to $+125^{\circ}$ C.
- 3) Test Time: ½ hour dwell at each temperature extreme.
- 4) Test Duration: 500 Cycles
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

THERMAL SHOCK (NON-OPERATING CLASS TEMPERATURE):

- 7) OTHER, Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors.
- 8) Test Condition: -55° C to $+105^{\circ}$ C and -65° C to $+125^{\circ}$ C.
- 9) Test Time: ½ hour dwell at each temperature extreme.
- 10) Test Duration:100 Cycles
- 11) All test samples are pre-conditioned at ambient.
- 12) All test samples are exposed to environmental stressing in the mated condition.

THERMAL SHOCK:

- 1) EIA-364-32, Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors.
- 2) Test Condition I: -55° C to $+85^{\circ}$ C.
- 3) Test Time: ½ hour dwell at each temperature extreme.
- 4) Test Duration: A-3 100 Cycles
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

HUMIDITY:

- 1) Reference document: Other, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition, 240 Hours.
- 3) Method, $+25^{\circ}$ C to $+65^{\circ}$ C, 95% to 100% Relative Humidity excluding sub-cycles 7a.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

MATING/UNMATING:

- 1) Reference document: EIA-364-13, Mating and Unmating Forces Test Procedure for Electrical Connectors.
- 2) The full insertion position was to within 0.003" to 0.004" of the plug bottoming out in the receptacle to prevent damage to the system under test.
- 3) One of the mating parts is secured to a floating X-Y table to prevent damage during cycling.

MECHANICAL SHOCK (Specified Pulse):

- 1) Reference document: other, Mechanical Shock Test Procedure for Electrical Connectors
- 2) Test Condition: OS2
- 3) Peak Value: 40 G
- 4) Duration: 11 Milliseconds
- 5) Wave Form: Half Sine
- 6) Number of Shocks: 3 Shocks / Direction, 3 Axis (18 Total)

VIBRATION:

- 1) Reference document: other, Vibration Test Procedure for Electrical Connectors
- 2) Test Condition: V3 vita 47.1.
- 3) Power Spectral Density: 0.1 G² / Hz
- 4) G 'RMS': 12
- 5) Frequency: 5 to 2000 Hz
- 6) Duration: 1 Hours per axis (3 axis total)

Tracking Code: CR-971604_Report_Rev_1	Part #: B1SDT-30-28-H-06.0/P1M-30-01-S-D-RA-TR
	Part description: B1SDT/P1M

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes.

NANOSECOND-EVENT DETECTION:

- 1) Reference document: EIA-364-87, Nanosecond-Event Detection for Electrical Connectors
- 2) Prior to test, the samples were characterized to assure the low nanosecond event being monitored will trigger the detector.
- 3) After characterization it was determined the test samples could be monitored for 50 nanosecond events

LLCR:

- 1) EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. <= +5.0 mOhms: -----Stable
 - b. +5.1 to +7.5 mOhms: ------Minor
 - c. +7.6 to +10.0 mOhms: ------Acceptable
 - d. +10.1 to +50.0 mOhms: ------Marginal
 - e. +50.1 to +2000 mOhms: -------Unstable
 - f. >+2000 mOhms:-----Open Failure

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

- 1) PROCEDURE:
 - a. Reference document: other, Withstanding Voltage Test Procedure for Electrical Connectors.
 - b. Test Conditions IV=70000 ft
 - c. Test voltage applied for 60 seconds.

ELECTROSTATIC DISCHARGE:

- 1) Reference Document: EN61000-4-2, VITA 47
- 2) Connector shall not be susceptible to damage by electrostatic discharge (ESD) events from 0 to 15kV as discharged from a 150-pf capacitor through a 330-ohm resistor.
- 3) Any damage shall be noted.

RESULTS Mating – Unmating Forces Mating Unmating Durability Group Initial Mating Min ----- 8.87 lbs Max-----9.63 lbs Unmating Min ----- 9.77 lbs Max-----10.48 lbs After 250 Cycles Mating 0 Min ----- 8.75 lbs Max-----9.49 lbs Unmating Min ----- 7.76 lbs Max----- 8.21 lbs **After Humidity Mating** Min ----- 6.83 lbs Max-----8.04 lbs Unmating Min ----- 5.77 lbs Max----- 6.62 lbs Mating Unmating Basic Group (B1SDT-10-28-H-06.0/P1M-10-01-S-D-RA-TR) **Initial Mating** Min ----- 3.04 lbs Max------4.00 lbs Unmating Min ----- 2.98 lbs Max----- 3.96 lbs After 250 Cycles **Mating** Min ----- 3.77 lbs

Max----- 4.77 lbs

Min ------ 2.92 lbs Max----- 3.82 lbs

Unmating

RESULTS Continued

Temperature Cycling

Continuity Initial

• No Interruptions ------Passed

Continuity Following 500 Cycles

No Interruptions ------Passed

DWV @ Altitude

- Minimums
 - o Test Voltage ------300 VAC
 - o Altitude Tested ------70000 ft.

Pin to Pin

• DWV------Passed

Row to Row

• DWV------Passed

Electrostatic Discharge

5kV

- No Damage ------Passed

 151-37
- No Damage ------Passed

RESULTS Continued LLCR Mating Unmating Durability Group (192 LLCR test points) Initial ----- 39.36 mOhms Max **Durability, 250 Cycles** <= +5.0 mOhms ----- Stable +5.1 to +7.5 mOhms ------ Minor +7.6 to +10.0 mOhms ------ Acceptable +10.1 to +50.0 mOhms ------ Marginal +50.1 to +2000 mOhms------ Unstable >+2000 mOhms------ Open Failure Thermal Shock <= +5.0 mOhms ----- Stable 0 +5.1 to +7.5 mOhms ------ Minor +7.6 to +10.0 mOhms ------ Acceptable +10.1 to +50.0 mOhms ------ Marginal +50.1 to +2000 mOhms------ Unstable >+2000 mOhms------ Open Failure Humidity <= +5.0 mOhms ------ Stable +5.1 to +7.5 mOhms ------ Minor +7.6 to +10.0 mOhms ------ Acceptable +10.1 to +50.0 mOhms ----- Marginal +50.1 to +2000 mOhms------ Unstable >+2000 mOhms------ Open Failure

RESULTS Continued LLCR Vibration and Mechanical Shock Group (192 LLCR test points) Initial ----- 69.76 mOhms Max Shock and Vibe <= +5.0 mOhms ----- Stable +5.1 to +7.5 mOhms ------ Minor +7.6 to +10.0 mOhms ------ Acceptable +10.1 to +50.0 mOhms ------ Marginal +50.1 to +2000 mOhms------ Unstable >+2000 mOhms------ Open Failure **Mechanical Shock & Random Vibration:** Shock No Damage-----Pass 50 Nanoseconds------Pass Vibration No Damage------Pass 50 Nanoseconds------ Pass LLCR Non-Operating Class Temperature Group (192 LLCR test points) Initial ----- 39.4 mOhms Max Temperature Cycle1 (-55°C to +105°C) <= +5.0 mOhms ------ Stable +5.1 to +7.5 mOhms ------ Minor

+7.6 to +10.0 mOhms ------ Acceptable +10.1 to +50.0 mOhms ----- Marginal

Tracking Code: CR-971604_Report_Rev_1	Part #: B1SDT-30-28-H-06.0/P1M-30-01-S-D-RA-TR
	Part description: B1SDT/P1M

DATA SUMMARIES

MATING/UNMATING:

Mating Unmating Durability Group

	Initial			250 Cycles				
	M	ating	Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	39.45	8.87	43.46	9.77	38.92	8.75	34.52	7.76
Maximum	42.83	9.63	46.62	10.48	42.21	9.49	36.52	8.21
Average	40.79	9.17	44.46	10.00	40.72	9.15	35.23	7.92
St Dev	1.06	0.24	1.11	0.25	1.29	0.29	0.61	0.14
Count	8	8	8	8	8	8	8	8

	After Humidity				
	М	ating	Uni	mating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	
Minimum	30.38	6.83	25.66	5.77	
Maximum	35.76	35.76 8.04		6.62	
Average	32.72	7.36	27.57	6.20	
St Dev	1.85	0.42	1.26	0.28	
Count	8	8	8	8	

Mating Unmating Basic Group (B1SDT-10-28-H-06.0/P1M-10-01-S-D-RA-TR

		Initial				250 Cycles			
	M	ating	Unmating		Mating		Unmating		
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	
Minimum	13.52	3.04	13.26	2.98	16.77	3.77	12.99	2.92	
Maximum	17.79	4.00	17.61	3.96	21.22	4.77	16.99	3.82	
Average	15.67	3.52	14.95	3.36	19.30	4.34	15.35	3.45	
St Dev	1.49	0.34	1.60	0.36	1.60	0.36	1.31	0.29	
Count	8	8	8	8	8	8	8	8	

Tracking Code: CR-971604_Report_Rev_1	Part #: B1SDT-30-28-H-06.0/P1M-30-01-S-D-RA-TR
	Part description: B1SDT/P1M

DATA SUMMARIES Continued

Temperature Cycling

File name	Results	Series	Fail
CR-971604	25	B1SDT / P1M	Pass
	26	B1SDT / P1M	Pass
Engineer	27	B1SDT / P1M	Pass
Tyler Lang	28	B1SDT / P1M	Pass
	29	B1SDT / P1M	Pass
Lab Tech	30	B1SDT / P1M	Pass
John Crawford	31	B1SDT / P1M	Pass
	32	B1SDT / P1M	Pass

DWV @ Altitude

Altitude Tested = 70,000 feet			
Test Voltage= 300			
Pin to Pin Row to Row			
Mated Mated			
Passed Passed			
Passed Passed			
Passed	Passed		

Electrostatic Discharge

Electrostatic Discharge (ESD) Summary			
Assemblies tested 8			
Test Conditions	Exposure to 5kV, 10kV, and 15kV (Repeated 10 Times)		
5kV	No Damage		
10kV	No Damage		
15kV No Damage			
Pass/Fail	Pass		

DATA SUMMARIES Continued

LLCR Mating Unmating Durability Group:

- 1) A total of 192 points were measured.
- 2) EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. <= +5.0 mOhms: -----Stable
 - b. +5.1 to +7.5 mOhms:-----Minor
 - c. +7.6 to +10.0 mOhms: ------Acceptable
 - d. +10.1 to +50.0 mOhms:-----Marginal
 - e. +50.1 to +2000 mOhms------Unstable
 - f. >+2000 mOhms:-----Open Failure

	LLCR Measurement Summaries by Pin Type					
Date	8/31/2023	9/11/2023	9/18/2023	9/28/2023		
Room Temp (Deg C)	23	22	22	22		
Rel Humidity (%)	49	50	50	55		
Technician	John Crawford	John Crawford	Aaron McKim	John Crawford		
mOhm values	Actual	Delta	Delta	Delta		
	Initial	Cycles	Therm Shck	Humidity		
		Pin Type:	Signal 1			
Average	37.52	0.67	0.71	0.61		
St. Dev.	1.06	0.66	0.7	0.45		
Min	33.42	0.02	0	0.01		
Max	39.36	3.75	4.39	3.67		
Summary Count	192	192	192	192		
Total Count	192	192	192	192		

LLCR Delta Count by Category						
Stable Minor Acceptable Marginal Unstable Open						
mOhms	<=5	>5.1 & <=7.5	>7.6 & <=10	>10.1 & <=50	>50 & <=2000	>2000
Cycles	192	0	0	0	0	0
Therm Shck	192	0	0	0	0	0
Humidity	192	0	0	0	0	0

Tracking Code: CR-971604_Report_Rev_1	Part #: B1SDT-30-28-H-06.0/P1M-30-01-S-D-RA-TR
	Part description: B1SDT/P1M

DATA SUMMARIES Continued

LLCR Vibration and Mechanical Shock Group:

- 1) A total of 192 points were measured.
- 2) EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. <= +5.0 mOhms: -----Stable
 - b. +5.1 to +7.5 mOhms:-----Minor
 - c. +7.6 to +10.0 mOhms: ------Acceptable
 - d. +10.1 to +50.0 mOhms:------Marginal
 - e. +50.1 to +2000 mOhms------Unstable
 - f. >+2000 mOhms:-----Open Failure

	LLCR Measurement Summaries by Pin Type				
Date	9/1/2023	10/2/2023			
Room Temp (Deg C)	22	22			
Rel Humidity (%)	48	51			
Technician	John Crawford	John Crawford			
mOhm values	Actual	Delta			
	Initial	Shock-Vib			
	Pin Type: Signal 1				
Average	67.26	1.17			
St. Dev.	1.76	1.46			
Min	60.58	0			
Max	69.76	5.83			
Summary Count	192	192			
Total Count	192	192			

LLCR Delta Count by Category						
Stable Minor Acceptable Marginal Unstable Open						
mOhms	<=5	>5.1 & <=7.5	>7.6 & <=10	>10.1 & <=50	>50 & <=2000	>2000
Shock-Vib 187 5 0 0						

Nanosecond Event Detection:

Shock and Vibration Event Detection Summary			
Contacts tested	60		
Test Condition	OS2, 40g's, 11ms, Half-Sine		
Shock Events	0		
Test Condition	12G 'RMS', 5Hz to 2000Hz, 1hr/axis		
Vibration Events	0		
Total Events	0		

Tracking Code: CR-971604_Report_Rev_1	Part #: B1SDT-30-28-H-06.0/P1M-30-01-S-D-RA-TR
	Part description: B1SDT/P1M

DATA SUMMARIES Continued

LLCR Non-Operating Class Temperature Group:

- 1) A total of 192 points were measured.
- 2) EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. <= +5.0 mOhms: -----Stable
 - b. +5.1 to +7.5 mOhms:-----Minor
 - c. +7.6 to +10.0 mOhms: ------Acceptable
 - d. +10.1 to +50.0 mOhms:------Marginal
 - e. +50.1 to +2000 mOhms------Unstable
 - f. >+2000 mOhms: -----Open Failure

	LLCR Measurement Summaries by Pin Type					
Date	8/31/2023	9/5/2023	9/11/2023			
Room Temp (Deg C)	23	22	22			
Rel Humidity (%)	47	54	54			
Technician	John Crawford	John Crawford	John Crawford			
mOhm values	Actual	Delta	Delta			
	Initial	Temperature Cycle I	Temperature Cycle II			
		Pin Type: Signal	1			
Average	37.42	0.43	0.56			
St. Dev.	0.91	0.45	0.61			
Min	34.1	0.01	0.01			
Max	39.4	4.28	4.64			
Summary Count	192	192	192			
Total Count	192	192	192			

LLCR Delta Count by Category						
Stable Minor Acceptable Marginal Unstable Open						
mOhms	<=5	>5.1 & <=7.5	>7.6 & <=10	>10.1 & <=50	>50 & <=2000	>2000
Temperature Cycle I	192	0	0	0	0	0
Temperature Cycle II	192	0	0	0	0	0

Part description: B1SDT/P1M

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: TCT-04

Description: Dillon Quantrol TC21 25-1000 mm/min series test stand

Manufacturer: Dillon Quantrol **Model:** TC2 I series test stand

Serial #: 04-1041-04

Accuracy: Speed Accuracy: +/- 5% of indicated speed; Speed Accuracy: +/- 5% of indicated speed;

... Last Cal: 05/29/2023, Next Cal: 05/29/2024

Equipment #: MO-11

Description: Switch/Multimeter

Manufacturer: Keithley

Model: 3706 Serial #: 120169 Accuracy: See Manual

... Last Cal: 09/11/2023, Next Cal: 09/11/2024

Equipment #: THC-05

Description: Temperature/Humidity Chamber (Chamber Room)

Manufacturer: Thermotron

Model: SM-8-3800 Serial #: 05 23 00 02 Accuracy: See Manual

... Last Cal: 11/14/2023, Next Cal: 05/31/2024

Equipment #: TSC-01

Description: Vertical Thermal Shock Chamber

Manufacturer: Cincinnati Sub Zero

Model: VTS-3-6-6-SC/AC Serial #: 10-VT14993 Accuracy: See Manual

... Last Cal: 06/30/2023, Next Cal: 06/30/2024

Equipment #: HPT-01

Description: Hipot Safety Tester

Manufacturer: Vitrek

Model: V73 **Serial #:** 019808

Accuracy:

... Last Cal: 05/15/2023, Next Cal: 05/15/2024

Equipment #: OV-05

Description: Forced Air Oven, 5 Cu. Ft., 120 V (Chamber Room)

Manufacturer: Sheldon Mfg.

Model: CE5F Serial #: 02008008 Accuracy: +/- 5 deg. C

... Last Cal: 02/05/2023, Next Cal: 02/05/2024

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: SVC-01

Description: Shock & Vibration Table

Manufacturer: Data Physics **Model:** LE-DSA-10-20K

Serial #: 10037

Accuracy: See Manual

... Last Cal: 04/22/2023, Next Cal: 04/22/2024

Equipment #: ACLM-01
Description: Accelerometer
Manufacturer: PCB Piezotronics

Model: 352C03 Serial #: 115819 Accuracy: See Manual

... Last Cal: 07/18/2023, Next Cal: 07/18/2024

Equipment #: ED-03

Description: Event Detector **Manufacturer:** Analysis Tech

Model: 32EHD Serial #: 1100604 Accuracy: See Manual

... Last Cal: 10/31/2023, Next Cal: 10/31/2024